# Notice of References Cited Application/Control No. 10/711,271 Examiner Ashford S. Hayles Applicant(s)/Patent Under Reexamination EBEL ET AL. Art Unit Page 1 of 3

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,864,494 A	09-1989	Kobus, Jr., Paul	726/33
*	В	US-4,887,218 A	12-1989	Natarajan, Bharath	700/102
*	С	US-4,887,207 A	12-1989	Natarajan, Bharath	705/10
*	D	US-5,168,445 A	12-1992	Kawashima et al.	705/10
*	Е	US-5,548,518 A	08-1996	Dietrich et al.	700/100
*	F	US-5,630,070 A	05-1997	Dietrich et al.	705/8
*	G	US-5,666,493 A	09-1997	Wojcik et al.	705/26
*	Н	US-5,819,232 A	10-1998	Shipman, Lester Lynn	705/8
*	ı	US-5,841,659 A	11-1998	Tanaka et al.	700/121
*	J	US-5,897,624 A	04-1999	Ramaswamy, Sanjay Elathur	705/28
*	K	US-6,128,540 A	10-2000	Van Der Vegt et al.	700/36
*	Ĺ	US-6,144,893 A	11-2000	Van Der Vegt et al.	700/108
*	М	US-6,272,389 B1	08-2001	Dietrich, Brenda Lynn	700/101

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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#### **NON-PATENT DOCUMENTS**

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# Notice of References Cited

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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0020230 A1	09-2001	Kaneko et al.	705/8
*	В	US-2001/0034673 A1	10-2001	Yang et al.	705/28
*	С	US-6,341,271 B1	01-2002	Salvo et al.	705/28
*	D	US-2002/0072988 A1	06-2002	Aram, Paul Richard	705/26
*	Е	US-2002/0165804 A1	11-2002	Beebe et al.	705/28
*	F	US-2003/0061126 A1	03-2003	Erke et al.	705/28
*	O	US-2003/0088449 A1	05-2003	Menninger, Anthony Frank	705/8
*	Ι	US-2003/0101107 A1	05-2003	Agarwal et al.	705/28
*	I	US-2003/0083963 A1	05-2003	Benson, Thomas D.	705/28
*	J	US-2003/0126103 A1	07-2003	Chen et al.	706/50
*	К	US-6,594,535 B1	07-2003	Costanza, John R.	700/97
*	L	US-2003/0158795 A1	08-2003	Markham et al.	705/28
*	М	US-2003/0171963 A1	09-2003	Kurihara et al.	705/7

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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#### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited

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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0225635 A1	12-2003	Renz et al.	705/28
*	В	US-2004/0117227 A1	06-2004	Wei, Hong-Shan	705/007
*	С	US-2004/0128213 A1	07-2004	Wei, Hung-Shan	705/028
*	D	US-2005/0004833 A1	01-2005	McRae et al.	705/011
*	Е	US-6,889,106 B2	05-2005	Wei, Hung-Shan	700/100
*	F	US-2005/0283412 A1	12-2005	Cheng et al.	705/028
*	G	US-2006/0080160 A1	04-2006	Orumchian et al.	705/010
*	Н	US-7,058,587 B1	06-2006	Horne, Martin	705/7
*	I	US-2006/0287908 A1	12-2006	Orumchian et al.	705/010
*	J	US-7,222,786 B2	05-2007	Renz et al.	235/385
*	К	US-7,225,140 B2	05-2007	Yanagino et al.	705/10
*	L	US-7,380,213 B2	05-2008	Pokorny et al.	715/764
*	М	US-7,376,477 B2	05-2008	Adair et al.	700/95

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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#### **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.